

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 036654 D	APPLICATION NO. Rule 1.53(b) Continuation of U.S. Patent Application No. 09/373,982 <i>885027</i>		
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT Mitsutoshi MIYASAKA				
		FILING DATE June 21, 2001		GROUP		
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>[Signature]</i>		5,192,717	03-93	KAWAKAMI		
<i>[Signature]</i>		5,289,030	02-94	YAMAZAKI		
<i>[Signature]</i>		5,372,958	12-94	MIYASAKA		
<i>[Signature]</i>		5,482,749	01-96	TELFORD		
<i>[Signature]</i>		5,488,000	01-96	ZHANG		
<i>[Signature]</i>		5,624,873	04-97	FONASH		
<i>[Signature]</i>		5,648,276	07-97	HARA		
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
<i>[Signature]</i>		JP-A-6-132306	05-94	JAPAN		
<i>[Signature]</i>		JP-A-58-164267	09-83	JAPAN		
<i>[Signature]</i>		JP-A-5-55582	03-93	JAPAN		
<i>[Signature]</i>		JP-A-4-245482	09-92	JAPAN		
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<i>[Signature]</i>		JP-A-63-115328	05-88	JAPAN		
<i>[Signature]</i>		JP-A-2-137797	05-90	JAPAN		
<i>[Signature]</i>		JP-A-6-232059	08-94	JAPAN		
<i>[Signature]</i>		JP-A-6-16-3401	08-94	JAPAN		
<i>[Signature]</i>		JP-A-6-275524	09-94	JAPAN		
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
<i>[Signature]</i>		Ohshima, H., et al. "Full-Color LCDs with Completely Integrated Drivers Utilizing Low-Temperature Poly-Si TFTs", SID 93 DIGEST 1993, PP. 387-390.				
<i>[Signature]</i>		S. Wolf, et al., "Silicon Processing for the VLSI Era Vol 1, Lattice Press, 1986 (month not available)				
EXAMINER	<i>[Signature]</i>				DATE CONSIDERED <i>8/02</i>	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>[Signature]</i>		4,297,392	10-81	HIGASHI et al.		
<i>[Signature]</i>		5,313,075	05-94	ZHANG et al.		
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<i>[Signature]</i>		EO 0 254 589 A2	07-87	EUROPEAN PATENT OFFICE		
<i>[Signature]</i>		EP 0 552 375 A1	07-92	EUROPEAN PATENT OFFICE		
<i>[Signature]</i>		EP 0 526 779 A1	07-92	EUROPEAN PATENT OFFICE		
<i>[Signature]</i>		EP 0 562 623 A2	03-93	EUROPEAN PATENT OFFICE		
<i>[Signature]</i>		EP 0 592 227 A2	10-93	EUROPEAN PATENT OFFICE		
<i>[Signature]</i>		EP 0 598 394 A2	11-93	EUROPEAN PATENT OFFICE		
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<i>[Signature]</i>		Masatada Horiuchi et al, "One-Decade Reduction of PN-Junction Leakage Current Using Poly-SI Interlayered SOI Structures" Proceedings of the International Electron Devices Meeting, Wash, DC 12/5-8/1993.				
<i>[Signature]</i>		5 December 1993, Institute of Electrical and Electronics Engineers, pgs. 847-850, XP000481744				
<i>[Signature]</i>		Masumo K et al., "Low-Temperature Preparation of Poly-SI TFT by AR Laser Annealing at High Scanning Speed" Electronics & Communications in Japan, Part II - Electronics, vol. 76, no. 9, 1 Sept. 1993, pgs. 112-116, XP000447931.				
<i>[Signature]</i>		Yeckel, A. et al, "The Origin of Nonuniform Growth of LPCVD films from silane gase Mixtures" Journal of the Electrochemical Society, July 1989, vol. 136, no. 7, ISSN 0013-4651.				
<i>[Signature]</i>		Mitsutoshi Miyasaka et al, "Transistor and Physical Properties of Polycrystalline Silicon Films Prepared by Infralow-Pressure Chemical Vapor Deposition", Journal of Applied Physics, vol. 74, no. 4, 15 Aug. 1993, pgs 2870-2885.				
<i>[Signature]</i>		Patent Abstracts of Japan, vol. 018, no. 573 (E-1624), 2 Nov. 1994 & JP 06 216004 A (NEC Corp), 5 Aug. 1994				
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<i>JM</i>		5,583,369	12-96	YAMAZAKI et al.		
<i>JM</i>		5,114,770	05-92	ECHIZEN et al.		
<i>JM</i>		4,812,328	03-89	SAITO et al.		
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)						
EXAMINER <i>J. Johnson</i>				DATE CONSIDERED <i>8/02</i>		
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Form PTO-1449 (REV. 8-83)	US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 036654 D	APPLICATION NO. New Rule 53(b) Continuation of U.S. Application No. 09/373,982
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<i>JJ</i>	JP A 5-55582	3/1993	Japan		
<i>JJ</i>	JP A 58-164267	9/1983	Japan		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>J Jackson</i>	DATE CONSIDERED
		<i>8/02</i>

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